ALPHA & OMEGA SEMICONDUCTOR

AON7702

N-Channel Enhancement Mode Field Effect Transistor

SRFET™

General Description

The AON7702 uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for use in SMPS and general purpose applications. *Standard Product AON7702 is Pb-free (meets ROHS & Sony 259 specifications).*

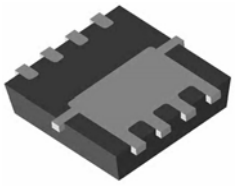
Features

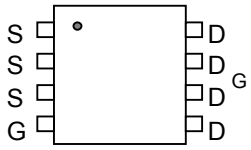
V_{DS} (V) = 30V
I_D = 13.5A (V_{GS} = 10V)
$R_{DS(ON)}$ < 10mΩ (V_{GS} = 10V)
$R_{DS(ON)}$ < 14mΩ (V_{GS} = 4.5V)

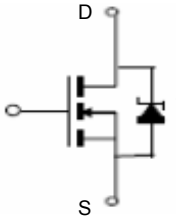
DFN 3x3

Top View

Bottom View







SRFET™
Soft **R**ecovery MOS**FET**:
Integrated Schottky Diode

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current [B,G]	T_C=25°C	I_D	20	A
	T_C=100°C		20	
Pulsed Drain Current [C]		I_{DM}	80	
Continuous Drain Current [B]	T_A=25°C	I_{DSM}	13.5	
	T_A=70°C		10	
Power Dissipation [B]	T_C=25°C	P_D	35	W
	T_C=100°C		14	
Power Dissipation [A]	T_A=25°C	P_{DSM}	3.1	
	T_A=70°C		2	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	30	40	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		60	75	°C/W
Maximum Junction-to-Case [D]	Steady-State	$R_{\theta JC}$	3.1	3.7	°C/W

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250µA, V_{GS}=0V	30			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=30V, V_{GS}=0V			100	µA
		T_J=55°C			500	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±20V			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	1	1.6	3	V
$I_{D(ON)}$	On state drain current	V_{GS}=10V, V_{DS}=5V	80			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=13.5A		8	10	mΩ
		T_J=125°C		12	15	
		V_{GS}=4.5V, I_D=11A		11	14	
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=13.5A		21		S
V_{SD}	Diode Forward Voltage	I_S=1A,V_{GS}=0V		0.38	0.5	V
I_S	Maximum Body-Diode Continuous Current				6	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=15V, f=1MHz		2390	4250	pF
C_{oss}	Output Capacitance			480		pF
C_{rss}	Reverse Transfer Capacitance			180		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz	0.5	1	1.5	Ω
SWITCHING PARAMETERS						
Q_g (10v)	Total Gate Charge	V_{GS}=10V, V_{DS}=15V, I_D=13.5A		37	48	nC
Q_g (4.5v)	Total Gate Charge			16	21	nC
Q_{gs}	Gate Source Charge			9.3		nC
Q_{gd}	Gate Drain Charge			5.5		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=15V, R_L=1.1Ω, R_{GEN}=3Ω		9		ns
t_r	Turn-On Rise Time			14		ns
$t_{D(off)}$	Turn-Off DelayTime			32		ns
t_f	Turn-Off Fall Time			16		ns
t_{rr}	Body Diode Reverse Recovery Time	I_F=13.5A, dI/dt=100A/µs		29	38	ns
Q_{rr}	Body Diode Reverse Recovery Charge	I_F=13.5A, dI/dt=100A/µs		15		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using <300 ms pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

F. The current rating is based on the t≤ 10s junction to ambient thermal resistance rating.

G.The maximum current rating is limited by bond-wires.

Rev0: Sept 2007

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

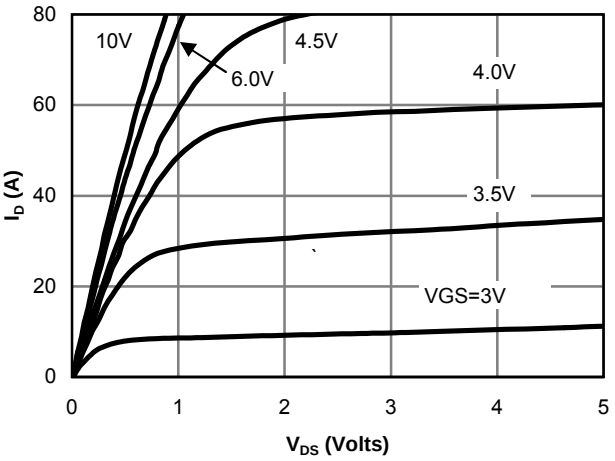


Figure 1: On-Region Characteristics

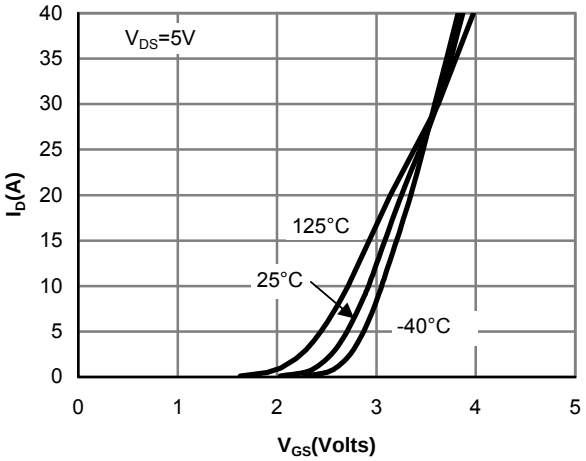


Figure 2: Transfer Characteristics

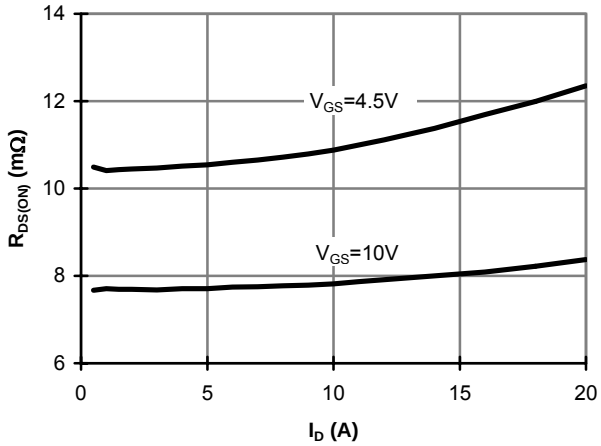


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

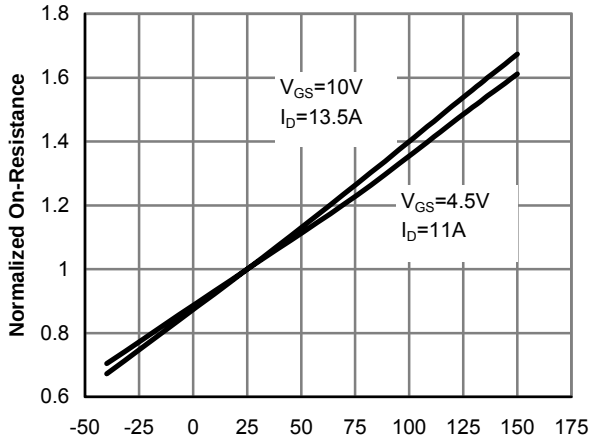


Figure 4: On-Resistance vs. Junction Temperature

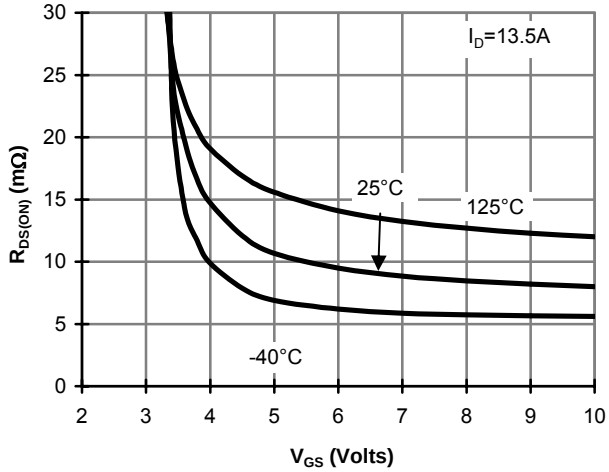


Figure 5: On-Resistance vs. Gate-Source Voltage

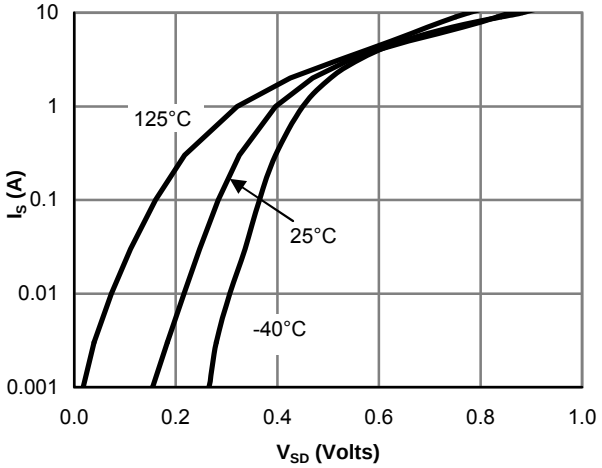


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

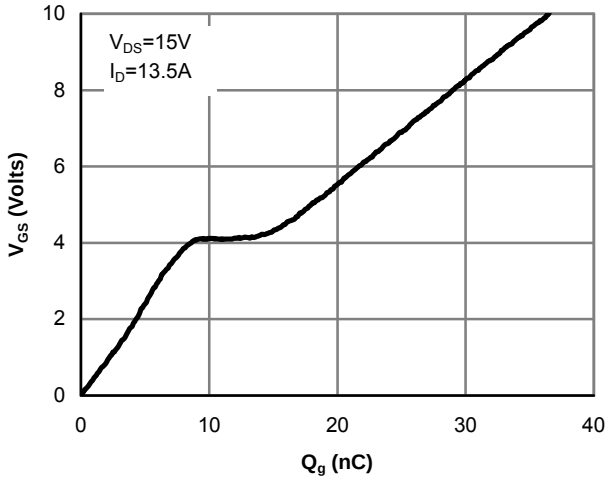


Figure 7: Gate-Charge Characteristics

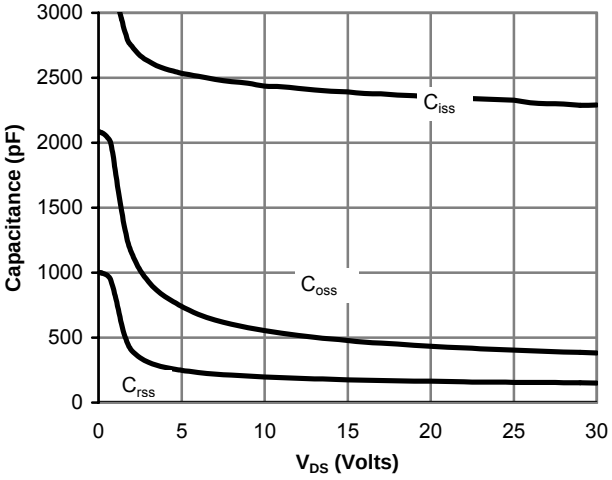


Figure 8: Capacitance Characteristics

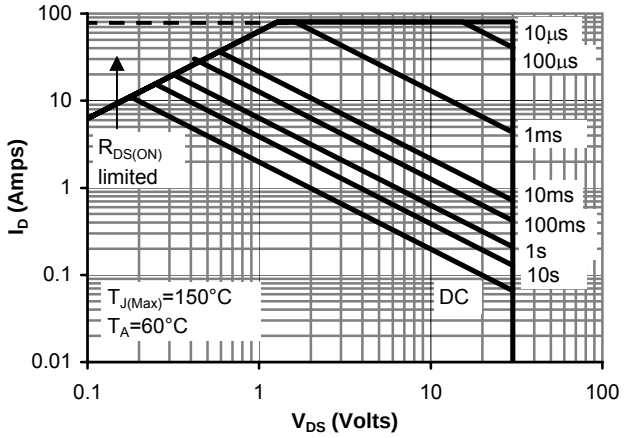


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

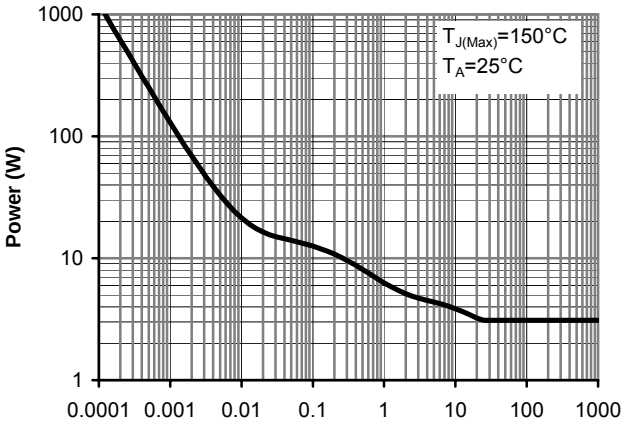


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

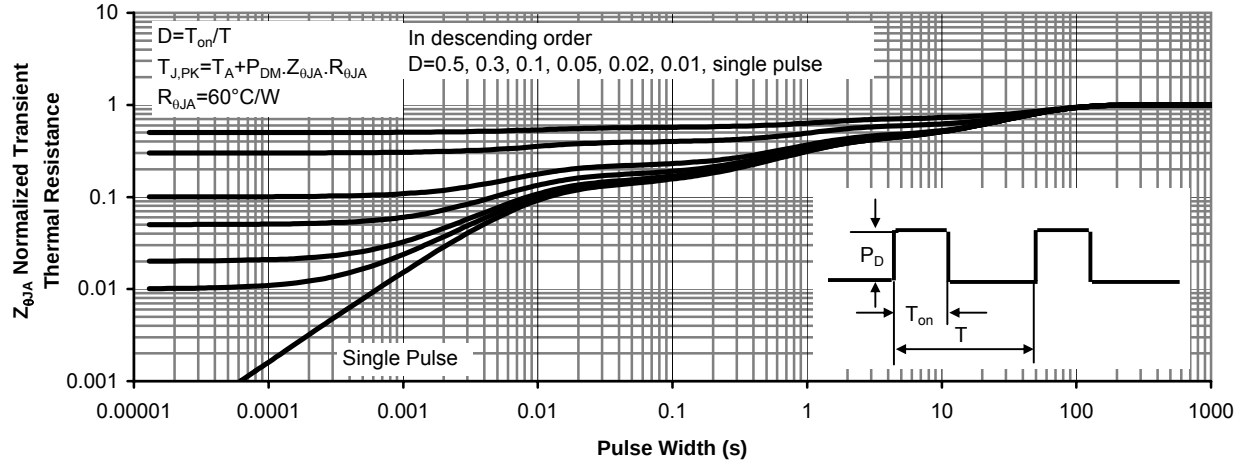


Figure 11: Normalized Maximum Transient Thermal Impedance (Note E)